54AC16472, 74AC16472 18-BIT REGISTERED TRANSCIEVERS WITH 3-STATE OUTPUTS

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- Members of the Texas Instruments
 Widebus ™ Family
- 3-State True Outputs
- Flow-Through Architecture Optimizes PCB Layout
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- EPIC ™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Package Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Pin Spacings

description

The 'AC16472 are 18-bit registered transceivers that contain two sets of D-type latches for temporary storage of data flowing in either direction. They can be used as two 9-bit transceivers or one 18-bit transceiver. Separate latch-enable (LEAB or LEBA) and output-enable (OEAB or OEBA) inputs are provided for each register to permit independent control in either direction of data flow.

When OEAB and LEAB are both low, the A-to-B latches are transparent; a subsequent low-to-high transition of LEAB puts the A latches in the

54AC16472 ... WD PACKAGE 74AC16472 ... DL PACKAGE (TOP VIEW)

	_			1
OEAB [1	O	56] 1 <u>OEB</u> A
1LEAB	2		55	
1A1 [3			1B1
GND [4		53	
1A2 [5		52	1B2
1A3 [6		51] 1B3
v _{cc} [7		50] v _{cc}
1A4 [8		49] 1B4
1A5 [9		48] 1B5
1A6 [10		47] 1B6
GND [11		46	GND
1A7 [12		45] 1B7
1A8 [13		44] 1B8
1A9 [14		43] 1B9
2A1 [15		42] 2B1
2A2 [16		41	2B2
2A3 [17		40	2B3
GND [18		39	GND
2A4 [19		38] 2B4
2A5 [20		37] 2B5
2A6 [21		36	2B6
v _{cc} [22		35] v _{cc}
2A7 [23		34	2B7
2A8 [24		33] 2B8
GND [25		32	GND
2A9 [26		31] 2B9
2LEAB [27		30	2LEBA
OEAB [28		29] 2 <mark>OEB</mark> A
				•

storage mode. With OEAB low, the B outputs are active and reflect the data present at the output of the A latches. Data flow from B to A is similar, but requires the use of the LEBA and OEBA inputs.

The 74AC16472 is packaged in TI's shrink small-outline package (DL), which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The 54AC16472 is characterized for operation over the full military temperature range of –55°C to 125°C. The 74AC16472 is characterized for operation from –40°C to 85°C.



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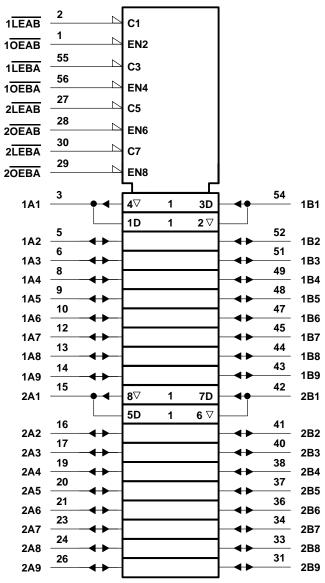
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FUNCTION TABLE†

	INPUTS					
LEAB	OEAB	Α	В			
Х	Н	Х	Z			
Н	L	Χ	в ₀ ‡			
L	L	Н	Н			
L	L	L	L			

[†] A-to-B data flow is shown: B-to-A flow is similar but uses LEBA and OEBA.

logic symbol§

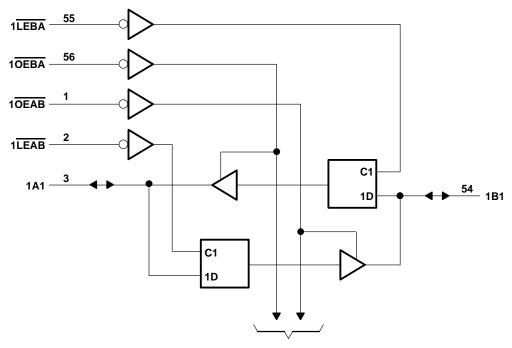


§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

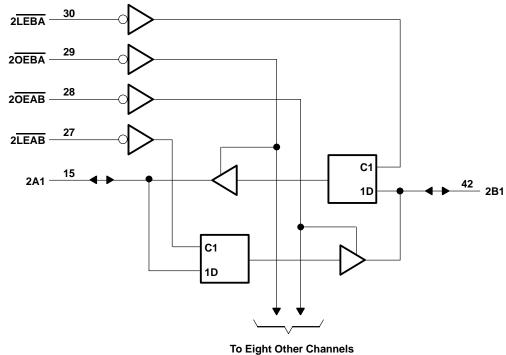


[‡]Output level before the indicated steady-state input conditions were established

logic diagram (positive logic)



To Eight Other Channels



To Eight Other Ondinion



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	\dots -0.5 V to 7 V
Input voltage range, V _I (see Note 1)–0.5	V to V_{CC} + 0.5 V
Output voltage range, V _O (see Note 1)	V to V_{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±450 mA
Maximum power package dissipation at T _A = 55°C (in still air) (see Note 2): DL package	1.4 W
Storage temperature range, T _{sto}	. −65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

			54	AC1647	'2	74	AC1647	2	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		3	5	5.5	3	5	5.5	V
		V _{CC} = 3 V	2.1			2.1			
ViH	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			3.15			V
		$V_{CC} = 5.5 \text{ V}$	3.85			3.85			
		V _{CC} = 3 V			0.9			0.9	
V _{IL}	Low-level input voltage	$V_{CC} = 4.5 \text{ V}$			\$ 1.35			1.35	V
		V _{CC} = 5.5 V		2	1.65			1.65	
٧ı	Input voltage		0	PA	VCC	0		VCC	V
۷o	Output voltage		0	1	VCC	0		VCC	V
		V _{CC} = 3 V		3	-4			-4	
ЮН	High-level output current	V _{CC} = 4.5 V	0	7	-24			-24	mA
		V _{CC} = 5.5 V	Q		-24			-24	
		VCC = 3 V			12			12	
lOL	Low-level output current	V _{CC} = 4.5 V			24			24	mA
		V _{CC} = 5.5 V			24			24	
Δt/Δν	Input transition rise or fall rate	-	0		10	0		10	ns/V
T _A	Operating free-air temperature		-55		125	-40		85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DA.	RAMETER	TEST CONDITIONS	Vaa	T,	A = 25°C	;	54AC16472		74AC16472		UNIT
	KAWETEK	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONII
			3 V	2.9			2.9		2.9		
		I _{OH} = -50 μA	4.5 V	4.4			4.4		4.4		
			5.5 V	5.4			5.4		5.4		
Vон		I _{OH} = -4 mA	3 V	2.58			2.48		2.48		V
		[4.5 V	3.94			3.8		3.8		
		I _{OL} = -24 mA	5.5 V	4.94			4.8		4.8		
		$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85	7	3.85		
			3 V			0.1		0.1		0.1	
		I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	
			5.5 V			0.1	7	0.1		0.1	
VOL		I _{OL} = 12 mA	3 V			0.36	\mathcal{I}_{η}	0.44		0.44	V
		lo. = 24 mA	4.5 V			0.36	⁷ 0	0.44		0.44	
		I _{OL} = 24 mA	5.5 V			0.36	Ya	0.44		0.44	
		I _{OL} = 75 mA [†]	5.5 V					1.65		1.65	
Ц	Control inputs	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μΑ
loz [‡]	A or B ports	$V_O = V_{CC}$ or GND	5.5 V			±0.5		±5		±5	μΑ
Icc		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80		80	μΑ
Ci	Control inputs	$V_I = V_{CC}$ or GND	5 V		3						pF
Cio	A or B ports	$V_O = V_{CC}$ or GND	5 V		11.5						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

		T _A = 25°C		54AC16472		74AC16472		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t _W	Pulse duration, LEAB or LEBA low	4		4	J. J.	4		ns
t _{su}	Setup time, data before LEAB or LEBA ↑	0.5		0.5	, ,	0.5		ns
th	Hold time, data after LEAB or LEBA ↑	3.5		3.5		3.5	·	ns

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

		T _A = 25°C		54AC16472		74AC16472		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t _W	Pulse duration, LEAB or LEBA low	4		4	JEW.	4		ns
t _{su}	Setup time, data before LEAB or LEBA ↑	0.5		0.5	, ,	0.5		ns
th	Hold time, data after LEAB or LEBA ↑	2.5		2.5	·	2.5	, and the second	ns

[‡] For I/O ports, the parameter I_{OZ} includes the input leakage current.

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	4 = 25°C	;	54AC1	6472	74AC1	6472	UNIT
FARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT
^t PLH	A or B	B or A	3.5	8	12.5	3.5	14.2	3.5	14.2	ns
^t PHL	AOIB	BOIA	3.9	8.4	12.8	3.9	13.9	3.9	13.9	115
^t PLH	LEBA or LEAB	BA or LEAB A or B	4.8	10.3	15.6	4.8	17.9	4.8	17.9	ns
^t PHL			4.7	9.7	14.7	4.7	16.3	4.7	16.3	115
^t PZH	OFDA OFAB	A or B	3.9	8.9	14	3.9	15.9	3.9	15.9	20
t _{PZL}	OEBA or OEAB		5	11.2	17.6	5	19.7	5	19.7	ns
^t PHZ	OEBA or OEAB	TOTAL A OF B	4.4	7	9.4	4.4	10	4.4	10	ns
t _{PLZ}		A or B	4	6.4	8.7	4	9.4	4	9.4	115

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

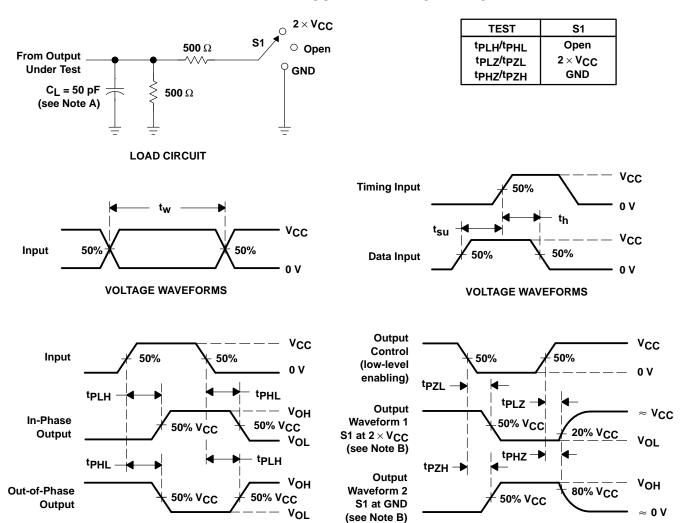
PARAMETER	FROM	то	T,	չ = 25°C	;	54AC1	6472	74AC1	6472	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	A or B	B or A	2.9	5.6	8.4	2.9	9.5	2.9	9.5	ns
^t PHL	AUIB	BOIA	3.1	6	8.7	3.1	9.6	3.1	9.6	115
^t PLH	LEBA or LEAB	or LEAB A or B	3.9	7.3	10.3	3.9	11.7	3.9	11.7	ns
^t PHL			3.7	6.9	9.7	3.7 4	10.9	3.7	10.9	113
^t PZH	OFDA OFAB	A or B	3.1	6.2	8.9	3.1	10.2	3.1	10.2	ns
^t PZL	OEBA or OEAB		3.9	7.3	10.4	3.9	11.6	3.9	11.6	115
^t PHZ	OEBA or OEAB	A or OEAB A or B	4.3	6.2	8.1	4.3	8.6	4.3	8.6	ns
^t PLZ		AOIB	3.8	5.7	7.4	3.8	8	3.8	8	115

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance per transceiver	Outputs enabled	C _I = 50 pF, f = 1 MHz	59	pF
	Tower dissipation capacitance per transceiver	Outputs disabled	$C_L = 50 \text{ pr}, f = 1 \text{ MHZ}$	6

VOLTAGE WAVEFORMS

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

VOLTAGE WAVEFORMS

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50~\Omega$, $t_f = 3~ns$, $t_f = 3~ns$.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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